Joel Goergen Beth (Donnay) Kochuparambil Cisco Systems Inc. 15 December, 2011

Dk & Df ALGEBRAIC MODEL v2.01

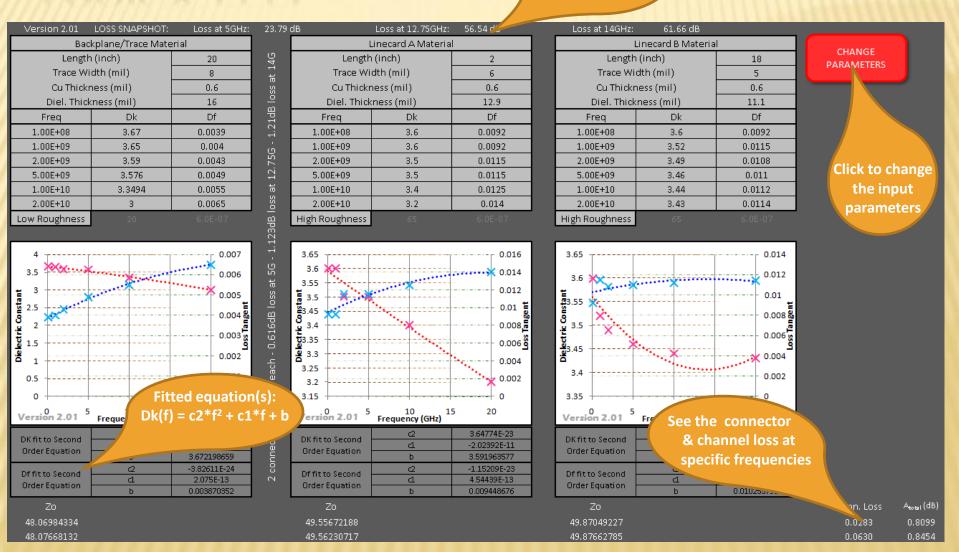
Let's take a look...

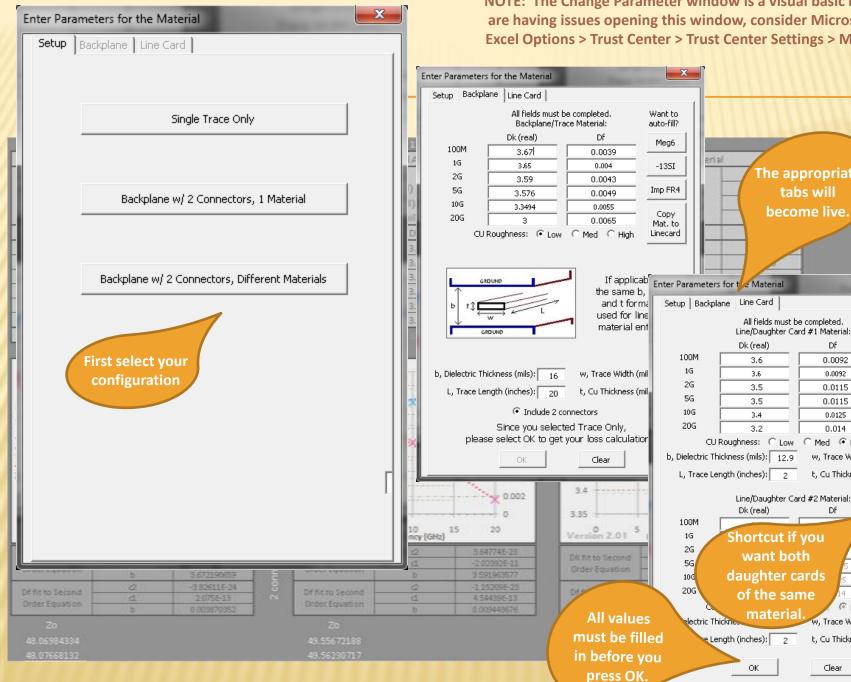
WHAT YOU WILL SEE

NOTE: The Change Parameter window is a visual basic macro. If you save the file to your computer, be sure to select the Maco-Enabled file type.

LOOK & FEEL

Quick preview of select frequencies





NOTE: The Change Parameter window is a visual basic macro. If you are having issues opening this window, consider Microsoft button > Excel Options > Trust Center > Trust Center Settings > Macro Settings

The appropriate

tabs will

become live.

All fields must be completed.

3.6

3.6

3.5

3.5

3.4

3.2

2

want both

material.

OK.

Df

0.0092

0.0092

0.0115

0.0115

0.0125

0.014

🔘 Med 🛛 💿 High

Df

w, Trace Width (mils):

🖸 Hiah

w, Trace Width (mils):

Clear

t, Cu Thickness (mils): 0.6

t, Cu Thickness (mils): 0.6

x

Want to

auto-fill?

Meg6

-13SI

Imp FR4

Use same

as LC #1

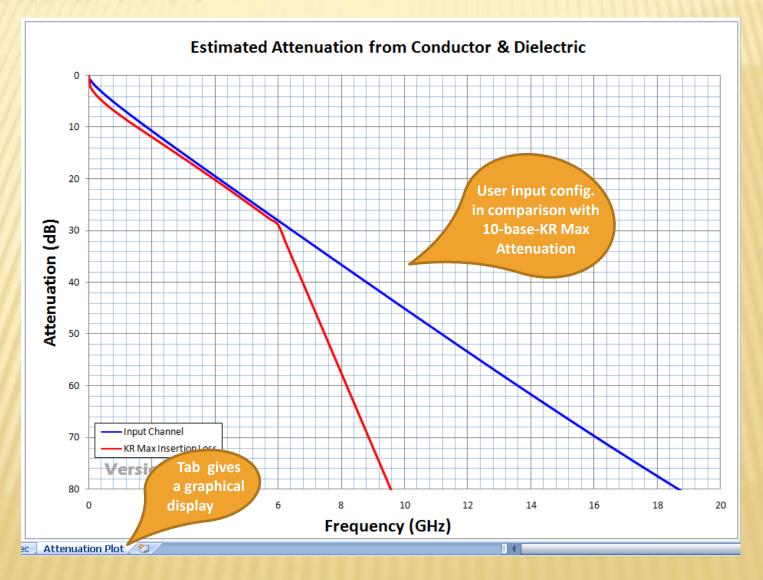
Meg6

Imp FR4

6

6

LOOK & FEEL



Behind the Scenes...

EQUATIONS AND REFERENCES OF MODEL

FREQUENCY DEPENDENCE

- × 6 input frequency points for Dk and Df
- × Fit Dk and Df to second order equations
 - + Coefficients shown on sheet
 - + Graphical representation shown on sheet
- Note that frequency dependence fit is only approximated to 20G, therefore, loss approximations should only be considered to 20G
- × Z_0 is calculated with Dk (or ε_r) at a given frequency; a similar technique is used in loss calculations

DK & DF SECOND ORDER EQUATIONS

 Second order approximation is created using the LINEST function. This function essentially fits a 2nd order polynomial to the 6 frequency points given; resulting in

 $D_{k} = c_{2}*f^{2} + c_{1}*f + b$ × Function as implemented in the spreadsheet: LINEST(C8:C13,B8:B13^[1,2])

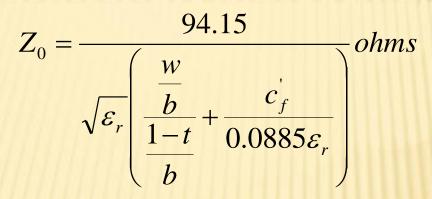
> Y Values (Dk entered points)

X Values (Freq. associated w/ entered points)

Exponents of X; Creating a second order equation.

See Excel HELP for more details on LINEST function.
 Methodology verified against "add trend line" within plot.

CHARACTERISTIC IMPEDANCE^[2, EQU 4-5]



$$c_{f}' = \frac{0.0885\varepsilon_{r}}{\pi} \left\{ \frac{2}{1 - \frac{t}{b}} \log_{e} \left(\frac{1}{1 - \frac{t}{b}} + 1 \right) - \left(\frac{1}{1 - \frac{t}{b}} - 1 \right) \log_{e} \left(\frac{1}{\left(1 - \frac{t}{b} \right)^{2}} - 1 \right) \right\}$$

Unchanged from v1.01 ε_r = relative dielectric constant (at a given frequency)

- b = platespacing (mil)
- w =trace width (mil)
- t =trace thickness (mil)

 $c_f = \text{fringing capacitance}(\mu f/cm) * \text{assuming semi} - \text{infinite plate between two infinite ground planes, but good approximation for w/(b - t) <math>\geq 0.35$

Unchanged **ATTENUATION IN LOSSY LINES**

× Attenuation per length^[1, EQN 9-54]:

* Attenuation per length^[1, EQN 9-54]:

$$\alpha_n = \sqrt{\frac{1}{2} \left[\sqrt{\left(R_L^2 + \omega^2 L_L^2\right) \left(G_L^2 + \omega^2 C_L^2\right)} - \omega^2 L_L C_L + R_L G_L \right]} \text{ nepers/length}$$

Using a low-loss approximation^[1, EQN 9-55]: (surface roughness ignored)

$$\alpha_n = \frac{1}{2} \left(\frac{R_L}{Z_0} + G_L Z_0 \right) \text{nepers/length}$$

But we don't typically discuss in nepers...[1, EQN 9-57]

 $10^{\frac{\alpha_{dB}}{20}} = e^{\alpha_n} \qquad \therefore \alpha_{dB} = 20 \log_{10} e \times \alpha_n$ for ease of notation: $Y_{n \rightarrow dB} = 20 \log_{10} e$

CONDUCTOR LOSS (per inch)

- α_{cond} = attenuation of amplitude due to conductor loss, in dB/length^[1,EQN 9-59] $\alpha_{cond} = (Y_{n \to dB}) \times \frac{R_L}{Z_0} \begin{cases} Y_{n \to dB} = \text{conversion from nepers to } dB \\ R_L = \text{resistance per length of conductor} \\ Z_0 = \text{characteristic impedance} \end{cases}$
 - × Skin effect, ground resistance, and stripline effect are accounted for in resistance^[3, EQNs 4.3a-4.10].
 - R of signal trace & return path (w/skin effect)

 $R_{signalCu\,skin\,effect} = \frac{\sqrt{\pi\mu\rho f}}{W} \qquad R_{groundCu\,skin\,effect} = \frac{\sqrt{\pi\mu\rho f}}{6H}$

AC surface resistance for microstrip (or 1 side of a stripline trace) $R_{acmicrostrip} = R_{signal} + R_{ground}$

CONDUCTOR LOSS (per inch)

 Stripline approximation assumes parallel resistance of top and bottom microstrip approximations

$$R_{L} = \frac{\left[\sqrt{\pi\mu\rho f} * \left(\frac{1}{w} + \frac{1}{6H}\right)\right]^{2}}{2*\left[\sqrt{\pi\mu\rho f} * \left(\frac{1}{w} + \frac{1}{6H}\right)\right]}$$

 $\begin{cases} R_L = \text{stripline surface resistance } (\Omega/\text{inch}) \\ w = \text{width of trace (inch)} \\ H = \text{height dielectric from ground to signal (inch)} \\ \mu = \text{permeability of } \text{Cu} \approx 4\pi \times 10^{-7} \times 0.999994 \quad \frac{\text{H}}{\text{m}} \\ \rho = \text{resistivity of } \text{Cu} = \frac{1}{\sigma} = \frac{1}{5.96 \times 10^7} \quad \Omega \text{ m} \\ f = \text{frequency (hertz)} \end{cases}$

× Conductor loss per inch as entered in the model:

$$\alpha_{cond} = \frac{1}{2} \times (20 \log_{10} e) \times \left(\frac{\left[\sqrt{\pi \mu \rho f} * \left(\frac{1}{w} + \frac{1}{6H} \right) \right]}{2} \right) \times \frac{1}{Z_0}$$

DIELECTRIC LOSS (per inch)

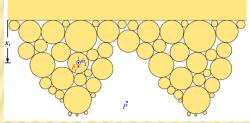
- α_{cond} = attenuation of amplitude due to dielectric loss, in dB/length^[1,EQN 9-60] $\alpha_{diel} = (Y_{n \to dB}) \times G_L Z_0 \begin{cases} Y_{n \to dB} = \text{conversion from nepers to } dB \\ G_L = \text{shunt conductance per length from dielectric} \end{cases}$ Unchanged from v1.01 $Z_0 = characteristic impedance$
 - × As developed by Bogatin...
 - $G_L = \omega \tan(\delta) C_L$ $Z_0 = \frac{\sqrt{\varepsilon_r}}{cC}$
- G_L equation^[1, EQN 9-19, EQN 9-60] $\begin{bmatrix} Z_0 \text{ equation}^{[1, EQN 9-67]} \text{ is used to cancel the capacitance value,} \\ \text{the } Z_0 \text{ value for a given frequency is NOT used} \end{bmatrix}$ c = speed of light m/s \therefore conversion m \rightarrow in is needed

Dielectric loss per inch as entered in the model:

$$\alpha_{diel} = \frac{1}{2} \times (20 \log_{10} e) \times (2\pi f \times D_f) \times \frac{\sqrt{\varepsilon_r}}{299792458 * 39.37}$$

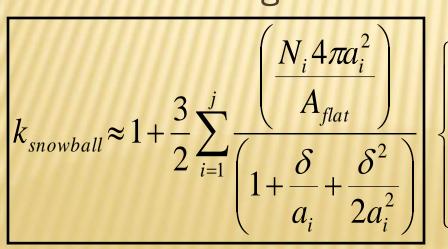
SURFACE ROUGHNESS (multiplier)

* Through the snowball method (Huray Model^[4, CHAP 6]), surface roughness is approximated as a collection of



smaller spheres. *Note image shows non-uniform "snowballs"... model approximates using uniform spheres.

× Applied to trace: $\alpha_{total} = \alpha_{diel} + k_{snowball} \alpha_{cond(smooth)}$ × Surface roughness multiplier as entered in the model:



 $\begin{cases} a_i = \text{radius of spheres (m)} \\ N_i = \text{number of snowballs of size } a_i \text{ per } A_{flat} \\ A_{flat} = \text{total area containing stacked snowballs} \\ \delta = \text{skin depth (m)} \quad \dots \text{ recall } : \quad \delta = \frac{1}{\sqrt{\pi\mu\sigma f}} \end{cases}$

CONNECTOR LOSS & CHANNEL LOSS

- × Attempting to base on 25G technology connectors
- Set Connector models from multiple vendors to draw this max* connector loss... used in model:

$$IL_{conn} = 9*10^{-6}*\sqrt{f} - 1.2*10^{-12}*f + 1.6*10^{-21}f^{2}$$

- * Max loss when ignoring majority of ILD. Idea was to create equation that production connectors can beat. Note that this creates additional error in comparing model to measured, however, model should error in pessimistic direction. Connector implementation likely to be changed in future versions.
- **Equation gives loss of: 0.6164dB @5G; 1.133dB @12.89G; 1.21dB @14G**

× OVERALL CHANNEL LOSS EQUATION: (simple enough, right?)

$$A_{total} = a_{LCA_total} * L_{LCA} + IL_{conn} + a_{BP_total} * L_{BP} + IL_{conn} + L_{LCB_total} * L_{LCB}$$

REFERENCES

[1] E. Bogatin. *Signal Integrity – Simplified*. Pearson Education, Inc., 2004. ISBN 0-13-066946-6.

S. B. Cohn. "Problems in Strop Transmission Lines." *IRE Trans. Microwave Theory and Techniques*, Vol. MTT-3, March, 1955, pp 119-126.

[3] S. H. Hall, G.W.Hall, J. A. McCall. High-Speed Digital System Design: A Handbook of Interconnect Theory and Design Practices. John Wiley & Sons, Inc., 2000. ISBN-10 0471360902.

[4] P. G. Huray. The Foundations of Signal Integrity. John Wiley & Sons, Inc., 2010. ISBN-978-0-470-34360-9

TRACKING THE CHANGES

Version | Change

- 1.01 9/26/2011 Initial release second order Dk & Df approximation, track user input channel along with Meg-6 & Improved FR-4 for given length/width/thickness, 3 materials compared to KR limit line.
- 2.01 12/15/2011 surface resistance updated to include return path resistance and stripline approximation, Huray model for surface roughness added, "worst-case" connector added, partitioning option added (backplane w/2 daughter cards), KR limit comparison made to attenuation max (instead of IL)